

December 2013

## **FCH104N60F**

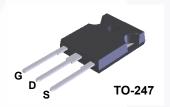
# N-Channel SuperFET<sup>®</sup> II FRFET<sup>®</sup> MOSFET 600 V, 37 A, 104 m $\Omega$

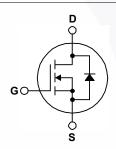
#### **Features**

- 650 V @ T<sub>J</sub> = 150°C
- Typ.  $R_{DS(on)}$  = 98 m $\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>q</sub> = 107 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 109 pF)
- · 100% Avalanche Tested
- · RoHS Compliant

## Description

SuperFET® II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET is very suitable for the switching power applications such as PFC, server/telecom power, FPD TV power, ATX power and industrial power applications. SuperFET II FRFET® MOSFET's optimized body diode reverse recovery performance can remove additional component and improve system reliability.





## **Absolute Maximum Ratings** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol		FCH104N60F	Unit	
V <sub>DSS</sub>	Drain to Source Voltage		600	V
V	Cata to Saurae Valtage	- DC	±20	V
$V_{GSS}$	Gate to Source Voltage	- AC (f > 1 H	z) ±30	V
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)	37	А
ID	Drain Current	- Continuous (T <sub>C</sub> = 100°C)	24	A
I <sub>DM</sub>	Drain Current	- Pulsed (Note	1) 111	Α
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		2) 809	mJ
I <sub>AR</sub>	Avalanche Current (Note 1)		1) 6.8	Α
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		1) 3.57	mJ
	MOSFET dv/dt		100	\//n=
dv/dt	Peak Diode Recovery dv/dt	(Note	3) 50	- V/ns
<b>D</b>	Daniel Diagination	$(T_C = 25^{\circ}C)$	357	W
$P_{D}$	Power Dissipation	- Derate Above 25°C	2.85	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C
T <sub>L</sub>	Maximum Lead Temperature for	Soldering, 1/8" from Case for 5 Seconds	300	οС

## **Thermal Characteristics**

Symbol	Parameter	FCH104N60F	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.35	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max. 40		- C/W

## **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCH104N60F	FCH104N60F	TO-247	Tube	N/A	N/A	30 units

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted.

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV <sub>DSS</sub> Drain to Source Breakdown Voltage	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}, T_C = 25^{\circ}\text{C}$	600	-	-	V	
	Dialii to Source Breakdown voltage	$I_D = 10 \text{ mA}, V_{GS} = 0 \text{ V}, T_C = 150^{\circ}\text{C}$	650	-	-	v
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C	-	0.67	-	V/°C
1	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 480 V, V <sub>GS</sub> = 0 V	-	-	10	^
IDSS	Zero Gate voltage Drain Current	$V_{DS} = 480 \text{ V}, V_{GS} = 0 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

## On Characteristics

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu\text{A}$	3	-	5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 18.5 \text{ A}$	-	98	104	mΩ
9 <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_{D} = 18.5 \text{ A}$	-	47	1	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 400 V V 0 V	-	4475	5950	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = 100 V, V <sub>GS</sub> = 0 V, f = 1 MHz		135	180	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			1.5	2.5	pF
Coss	Output Capacitance	V <sub>DS</sub> = 380 V, V <sub>GS</sub> = 0V, f = 1 MHz	-	75	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	$V_{DS} = 0 \text{ V to } 480 \text{ V}, V_{GS} = 0 \text{ V}$	-	109	-	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V	V <sub>DS</sub> = 380 V, I <sub>D</sub> = 18.5 A,	-	107	139	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10 V	-	25	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4)	-	44	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.87	-	Ω

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	34	78	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380 \text{ V}, I_D = 18.5 \text{ A},$	-	24	58	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V, R}_{G} = 4.7 \Omega$ (Note 4)	/-	98	206	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	5	20	ns

### **Drain-Source Diode Characteristics**

$I_S$	Maximum Continuous Drain to Source Diode Forward Current		-	37	Α
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current		-	111	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 18.5 A	-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time $V_{GS} = 0 \text{ V}, I_{SD} = 18.5 \text{ A},$	-	144	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge $dI_F/dt = 100 A/\mu s$	-	0.89	///-	μC

#### Notes

- 1. Repetitive rating: pulse-width limited by maximum junction temperature.
- 2.  $I_{AS}$  = 6.8 A,  $R_{G}$  = 25  $\Omega$ , starting  $T_{J}$  = 25°C.
- 3.  $I_{SD} \le 18.5$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le 380$  V, starting  $T_J$  = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

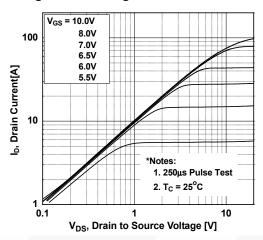
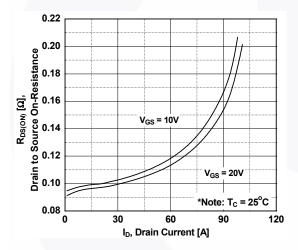


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage



**Figure 5. Capacitance Characteristics** 

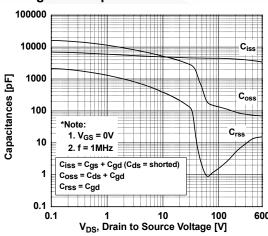


Figure 2. Transfer Characteristics

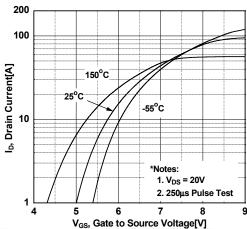


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

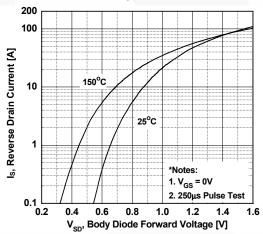
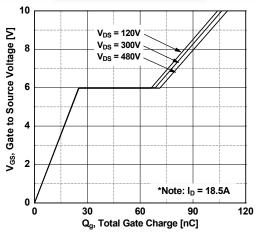


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

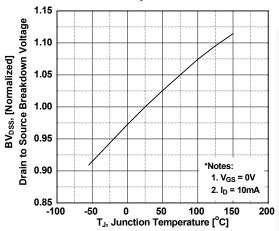


Figure 9. Maximum Safe Operating Area

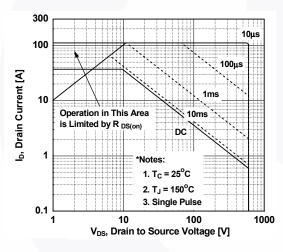


Figure 11. Eoss vs. Drain to Source Voltage

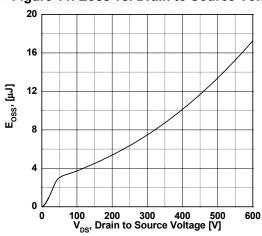


Figure 8. On-Resistance Variation vs. Temperature

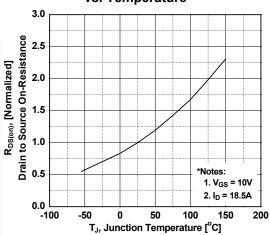
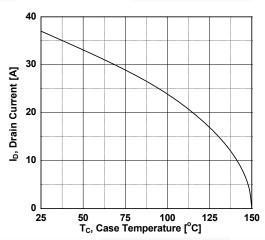
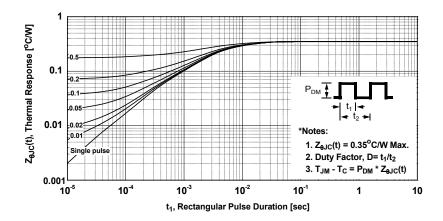


Figure 10. Maximum Drain Current vs. Case Temperature



## **Typical Performance Characteristics** (Continued)

Figure 12. Transient Thermal Response Curve



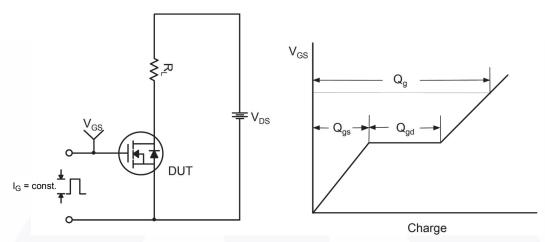


Figure 13. Gate Charge Test Circuit & Waveform

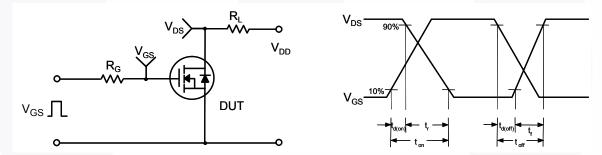


Figure 14. Resistive Switching Test Circuit & Waveforms

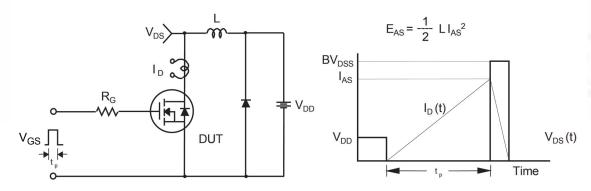


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

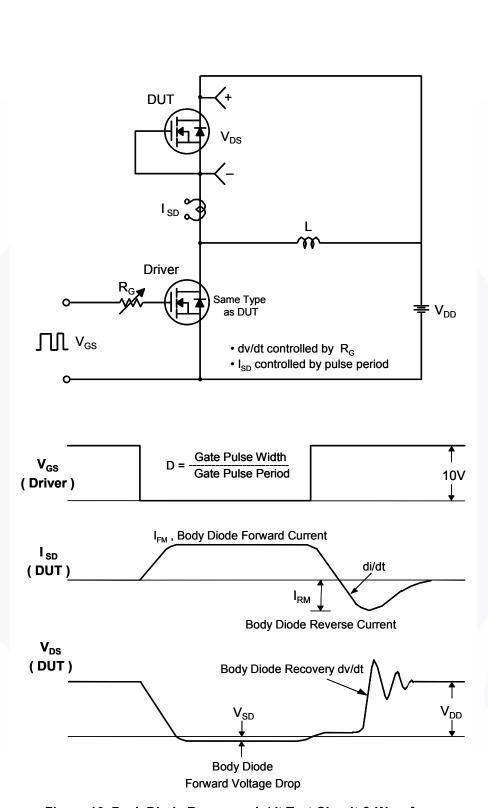
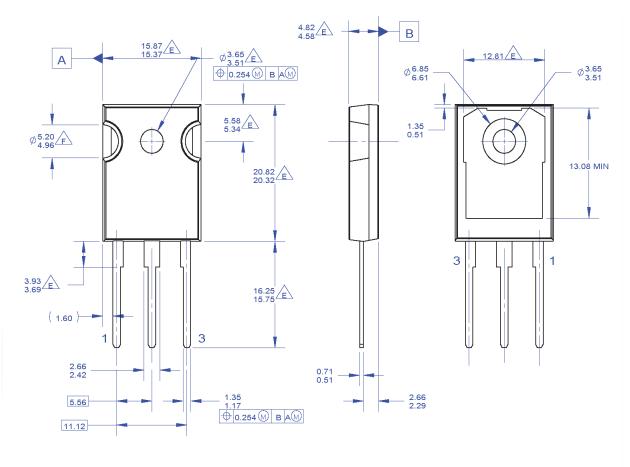


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

### **Mechanical Dimensions**



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- C. ALL DIMENSIONS ARE IN MILLIMETERS.
- D. DRAWING CONFORMS TO ASME Y14.5 1994

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Figure 17. TO-247, Molded, 3-Lead, Jedec Variation AB

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